## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | LEE ET AL. | Examiner | Art Unit | Akm Enayet Ullah | 2874 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,016,978	05-1991	Fargette et al.	359/234
	В	US-6,102,582	08-2000	Espindola et al.	385/57
	U	US-6,301,425	10-2001	Espindola et al.	385/140
	٥	US-6,836,583	12-2004	Hsu et al.	385/16
	Е	US-6,850,353	02-2005	Chiao, Jung-Chih	359/290
	F	US-6,901,182	05-2005	Yeh et al.	385/19
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	к	US-			
	L	US-	,		
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	σ					
	R				·	
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	· v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.